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(54) **Title:** ELECTRONICS TESTER

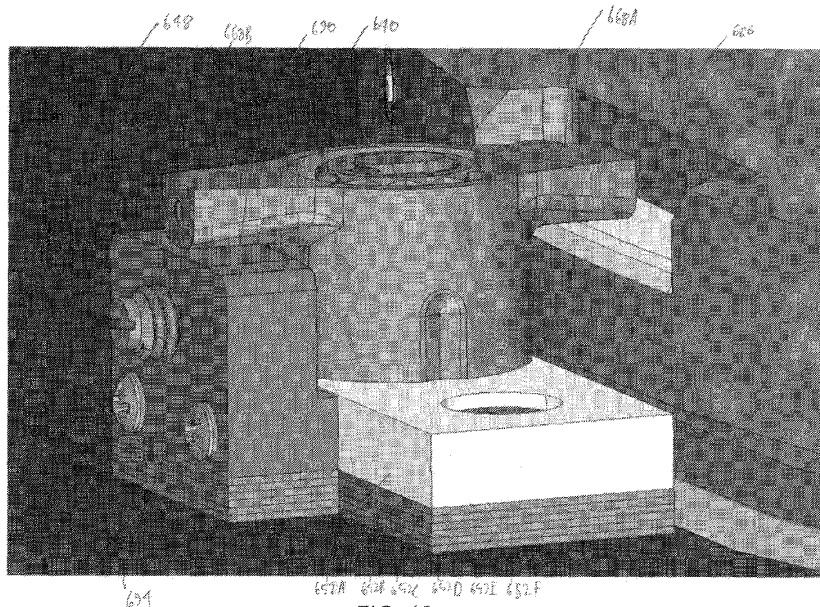


FIG. 19

(57) **Abstract:** A tester apparatus is described. Various components contribute to the functionality of the tester apparatus to facilitate movement of a wafer pack holding a vacuum without human oversight. These functionalities include a latch system to keep the wafer pack intact and a pressure sensing system to detect and relay a pressure in the wafer pack.

[Continued on next page]

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